## **DISCRETE SEMICONDUCTORS**

# DATA SHEET

# BTA212B series D, E and F Three quadrant triacs guaranteed commutation

**Product specification** 

August 2018



WeEn Semiconductors Product specification

# Three quadrant triacs guaranteed commutation

## BTA212B series D, E and F

#### **GENERAL DESCRIPTION**

Passivated guaranteed commutation triacs in a plastic envelope suitable for surface mounting intended for use in motor control circuits or with other highly inductive loads. These devices balance the requirements of commutation performance and gate sensitivity. The "sensitive gate" E series and "logic level" D series are intended for interfacing with low power drivers, including micro controllers.

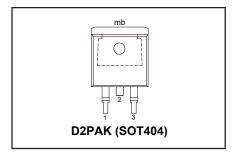
### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX.	MAX	UNIT
	BTA212B- BTA212B- BTA212B-	600D 600E 600F	800E	
$V_{DRM}$	Repetitive peak off-state	600	800	V
I <sub>T(RMS)</sub> I <sub>TSM</sub>	voltages RMS on-state current Non-repetitive peak on-state current	12 95	12 95	A A

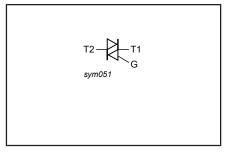
#### **PINNING - SOT404**

PIN	DESCRIPTION		
1	main terminal 1		
2	main terminal 2		
3	gate		
mb	main terminal 2		

#### **PIN CONFIGURATION**



#### **SYMBOL**



#### **LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT
$V_{DRM}$	Repetitive peak off-state voltages		-	<b>-600</b> 600 <sup>1</sup>	<b>-800</b> 800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; T <sub>mb</sub> ≤ 99 °C	-		12	Α
I <sub>TSM</sub>	Non-repetitive peak on-state current	full sine wave; $T_j = 25$ °C prior to surge				
		t = 20 ms t = 16.7 ms	-		95 05	l A A
l²t dl <sub>⊤</sub> /dt	l <sup>2</sup> t for fusing Repetitive rate of rise of on-state current after	$ \begin{aligned} &t = 10 \text{ ms} \\ &I_{TM} = 20 \text{ A}; \ &I_{G} = 0.2 \text{ A}; \\ &dI_{G}/dt = 0.2 \text{ A}/\mu\text{s} \end{aligned} $	-	4	45 00	A A²s A/μs
I <sub>GM</sub> P <sub>GM</sub> P <sub>G(AV)</sub>	triggering Peak gate current Peak gate power Average gate power	over any 20 ms	- - -		2 5 ).5	A W W
$T_{stg}$	Storage temperature Operating junction temperature	period	-40 -		50 25	Ç

August 2018 1 Rev 3.100

<sup>1</sup> Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15  $A/\mu s$ .

WeEn Semiconductors Product specification

# Three quadrant triacs guaranteed commutation

## BTA212B series D, E and F

#### THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{\text{th j-mb}}$ $R_{\text{th j-a}}$	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle in free air	- - -	- - 55	1.5 2.0 -	K/W K/W K/W

### STATIC CHARACTERISTICS

 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.		UNIT
		BTA212B-	D	D	Е	F	
I <sub>GT</sub>	Gate trigger current <sup>2</sup>	$V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}$					_
		T2+ G+ T2+ G-	-	5	10 10	25 25	mA mA
		T2- G-	_	5 5 5	10	25	mA
I <sub>L</sub>	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$					
		T2+ G+ T2+ G-	_	15 25	25 30	30 40	mA mA
		T2- G-	-	25	30	40	mA
I <sub>H</sub>	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	-	15	25	30	mA
					D, E, F		
$V_{T}$	On-state voltage	$I_T = 17 A$	-		1.6		V
V <sub>GT</sub>	Gate trigger voltage	$\dot{V}_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}$	0.05		1.5		V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A};$ $T_i = 125 \text{ °C}$	0.25		-		V
$I_D$	Off-state leakage current	$V_D = V_{DRM(max)}$ ; $T_j = 125  ^{\circ}C$	-		0.5		mA

### **DYNAMIC CHARACTERISTICS**

T<sub>i</sub> = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.		MAX.	UNIT
		BTA212B-	D	E	F		
dV <sub>D</sub> /dt	Critical rate of rise of off-state voltage	V <sub>DM</sub> = 67% V <sub>DRM(max)</sub> ; T <sub>j</sub> = 110 °C; exponential waveform; gate open circuit	20	60	70	-	V/μs
dl <sub>com</sub> /dt	Critical rate of change of commutating current	$V_{DM} = 400 \text{ V}; T_j = 125 ^{\circ}\text{C};$ $I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 10 \text{V}/\mu\text{s}; \text{ gate}$ open circuit	1.0	8	21	-	A/ms
dI <sub>com</sub> /dt	Critical rate of change of commutating current	$ \begin{aligned} &V_{\text{DM}} = 400 \text{ V; } T_{j} = 125 \text{ °C;} \\ &I_{\text{T(RMS)}} = 12 \text{ A;} \\ &dV_{\text{com}}/dt = 0.1 \text{V/}\mu\text{s; gate} \\ &\text{open circuit} \end{aligned} $	3.5	16	32	-	A/ms

<sup>2</sup> Device does not trigger in the T2-, G+ quadrant.

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### Three quadrant triacs quaranteed commutation

## BTA212B series D, E and F

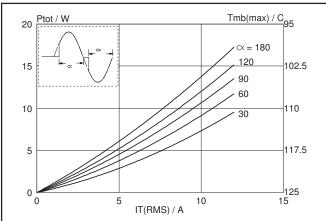


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.

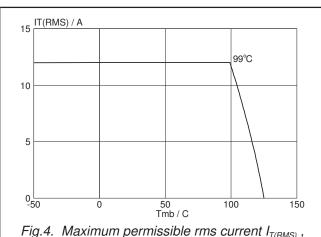


Fig.4. Maximum permissible rms current  $I_{T(RMS)}$ , versus mounting base temperature  $T_{mb}$ .

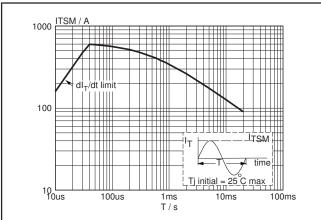


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \le 20$ ms.

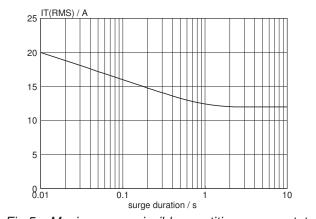


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents, f = 50 Hz;  $T_{mb} \le 99 ^{\circ}C$ .

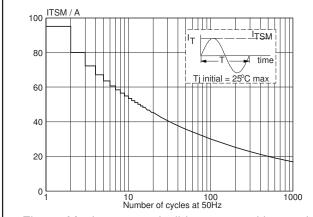
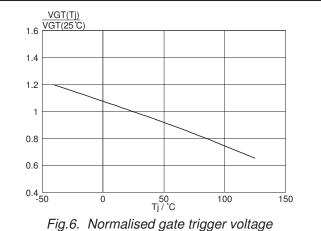


Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents, f = 50 Hz.

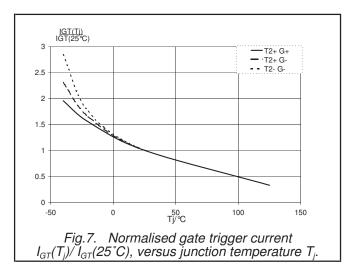


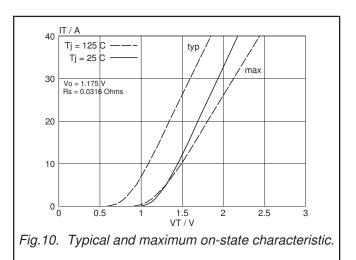
 $V_{GT}(T_i)/V_{GT}(25^{\circ}C)$ , versus junction temperature  $T_i$ .

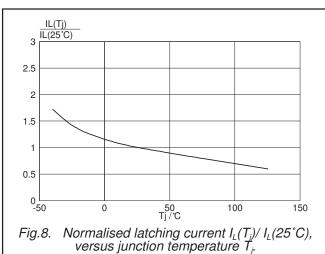
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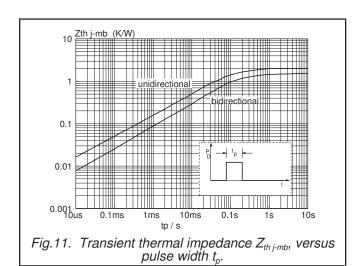
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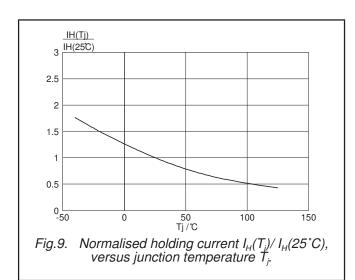
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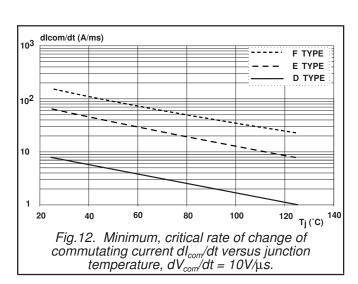








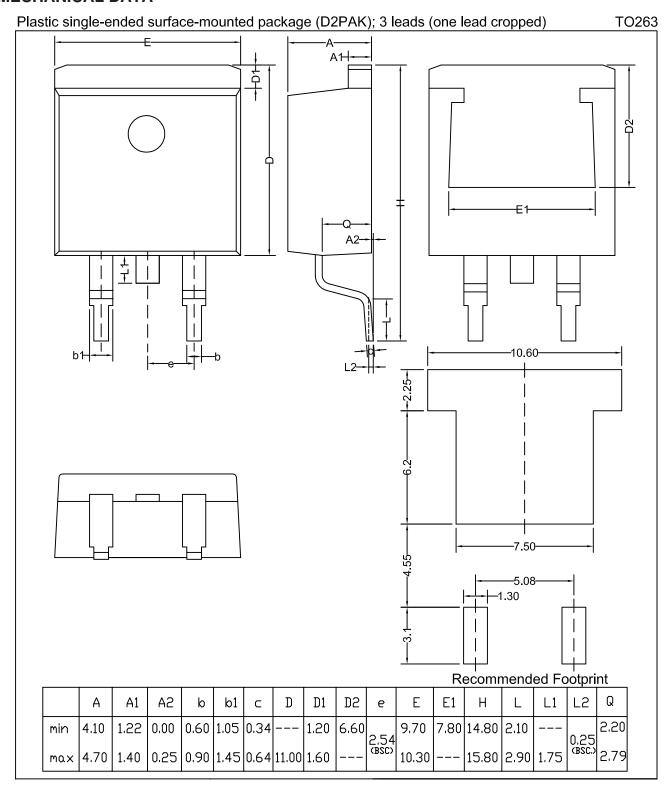




Three quadrant triacs guaranteed commutation

## BTA212B series D, E and F

#### **MECHANICAL DATA**



### Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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